

Notice of References Cited		Application/Control No. 10/020,336	Applicant(s)/Patent Under Reexamination HACK ET AL.	
		Examiner Tu X Nguyen	Art Unit 2684	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0098857	05-2003	Gettemy et al.	345/173
*	B	US-6,643,124	11-2003	Wilk, Peter J.	361/681
*	C	US-6,459,418	10-2002	Comiskey et al.	345/107
	D	US-2002/0090980	07-2002	Wilcox et al.	455/566
*	E	US-2002/0055938	05-2002	Matsuo et al.	707/104.1
*	F	US-2003/0117382	06-2003	Pawlowski et al.	345/204
*	G	US-5,452,092	09-1995	Kang et al.	358/426.02
*	H	US-2001/0017604	08-2001	JACOBSEN et al.	345/27
*	I	US-6,445,489	09-2002	Jacobson et al.	359/296
*	J	US-2002/0050958	05-2002	MATTHIES et al.	345/55
	K	US-2002/0176992	11-2002	Parthasarathy et al.	428/411.1
	L	US-6,384,804	05-2002	Dodabalapur et al.	345/82
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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